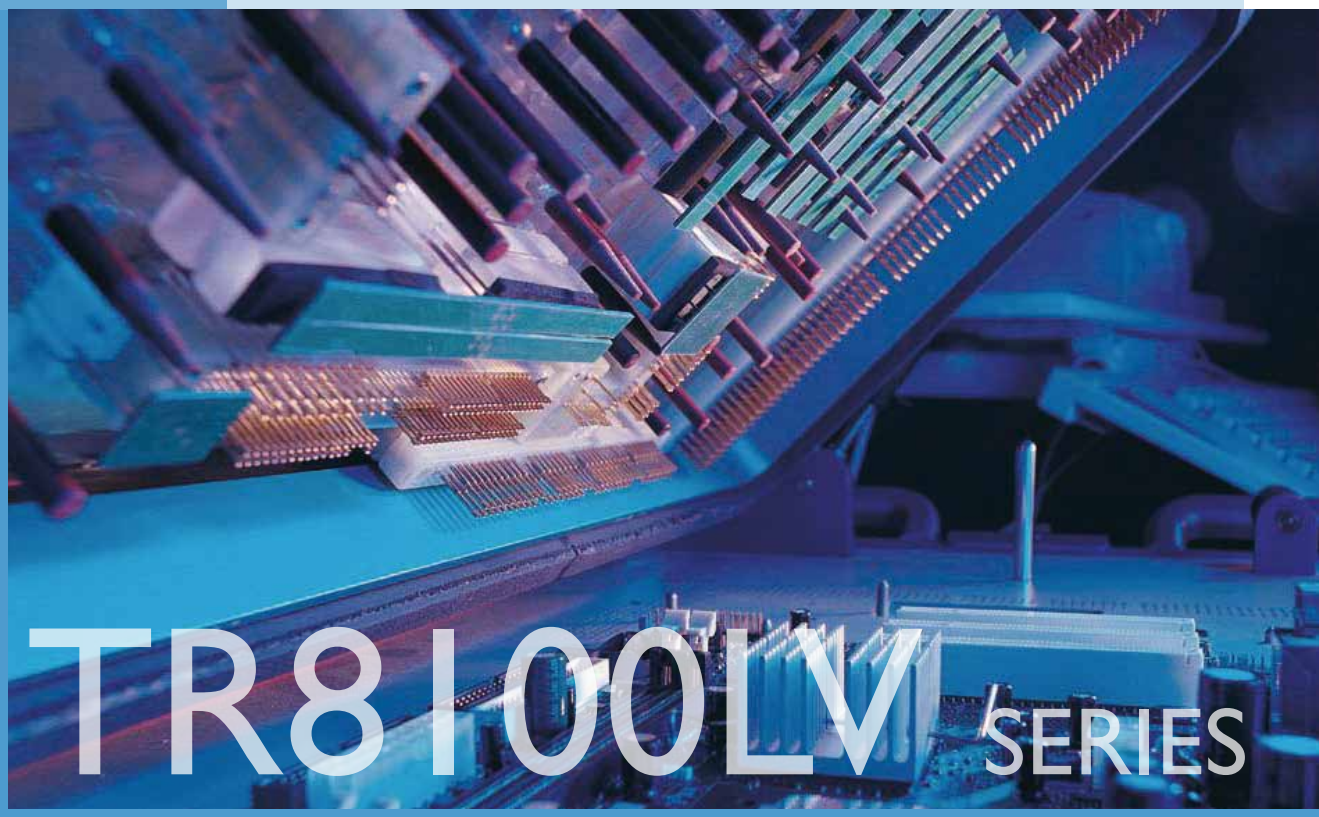
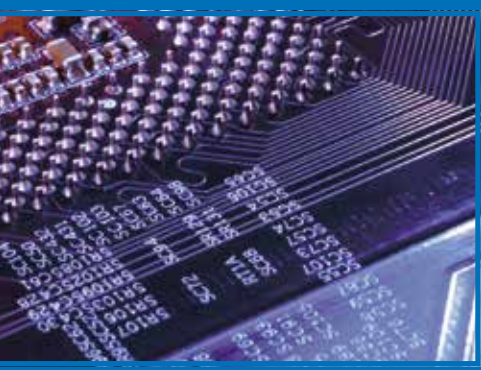
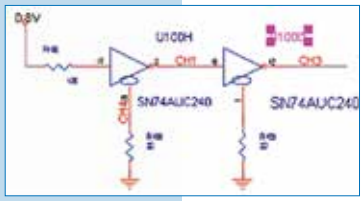
TR8100LV ICT

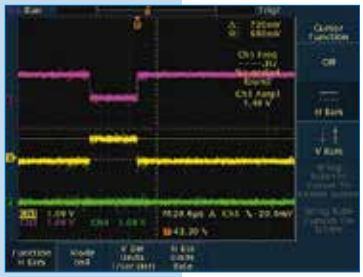




- HIGH-PERFORMANCE, HIGH THROUGHPUT IN-CIRCUIT TESTER
- HIGH FAULT COVERAGE TEST SOLUTION
- EASY AND FAST TEST PROGRAM DEVELOPMENT
- FRIENDLY USER INTERFACE DESIGN
- LOW-VOLTAGE SOLUTION

TRI innovation

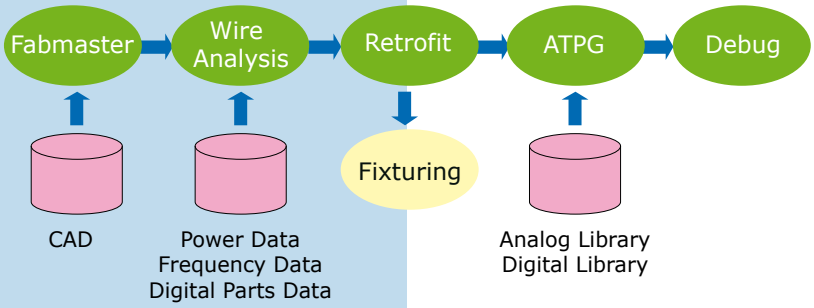




THE SOLUTION FOR TESTING LOW VOLTAGE TECHNOLOGIES

TR8100LV provides an ultra-low output impedance to enhance low-voltage backdriving capability.

- SN74AUC240 is a low-voltage device where VCC=0.8v.
- TR8100LV meets the specification of the SN74AUC240 in low-voltage testing requirement.



FAST AND EASY TEST PROGRAM DEVELOPMENT

Test Program Development Flowchart.

EASY-TO-USE ON-BOARD PROGRAMMING SOFTWARE MODULES

Modularized memory algorithms provide convenient On-Board Programming function.

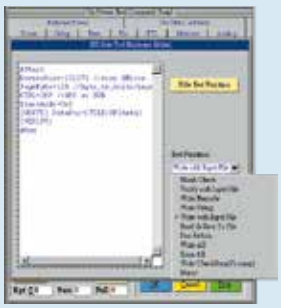
Flash Programming

- Supports a macro command language
- Supports conditional programming
- Supports multi vendor programming
- Menu-based debug tool

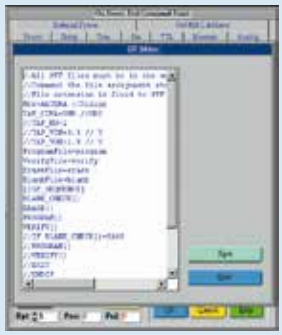
Serial Device Programming

- Menu-based test program generation
- Supports conditional programming
- Supports multi vendor programming

EEPROM Programming



SPI Programming



ISP Programming

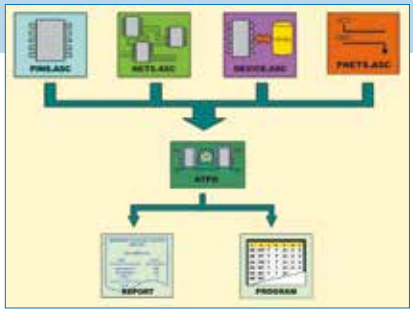
LIMITED TEST ACCESS SOLUTIONS

- TRI ToggleScan™ Test: Combines Boundary-Scan test and vectorless test to reduce the physical test probes. Includes Connector Test, Socket Test, Resistor Array Test, Capacitor Array Test, & Non-Boundary-Scan Chip Test.
- Drive-Through Test: Overpowers the resistors and capacitors to control and sense signals.
- CPU-Socket Test: Applies CSS (CPU Socket Sensor) on the top of the CPU to test the CPU without any physical test probes.
- Boundary Scan Test : The TR8100LV implements IEEE1149.1 & 1149.6 Boundary-Scan testing beginning with TRI's ABSTG (Automatic Boundary Scan Test program Generator). This auto-generates test programs and reporting for different kinds of test categories, such as individual boundary-scan device tests, boundary-scan cluster test, boundary-scan devices chain test and virtual nails test.
- Optimal Test Analyzer (OTA): Powerful software that performs line optimal analysis for cost efficiency and to decrease testing time.

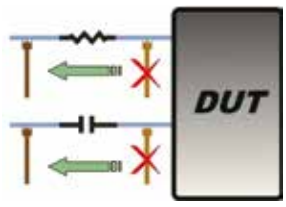
INTEGRATED ASSET SCANWORKS BOUNDARY-SCAN TECHNOLOGY*

Manufacturers will be able to globally deploy solutions from both Asset and TRI. The optional ScanWorks card solution integrated with TRI systems provides substantial cost savings.

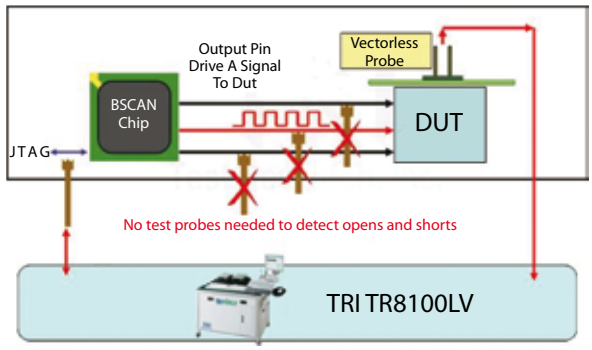
(*)Optional



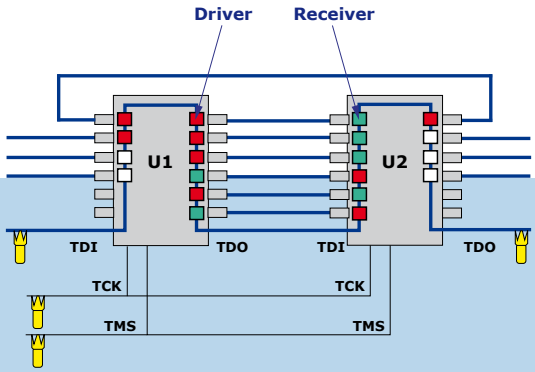
BSTG



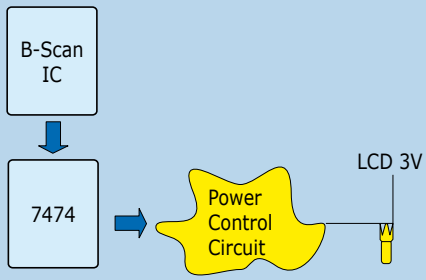
Drive-Through Test



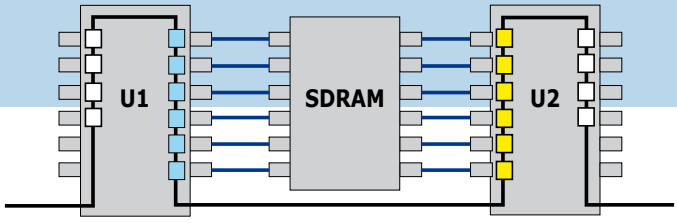
TRI ToggleScan™ Test



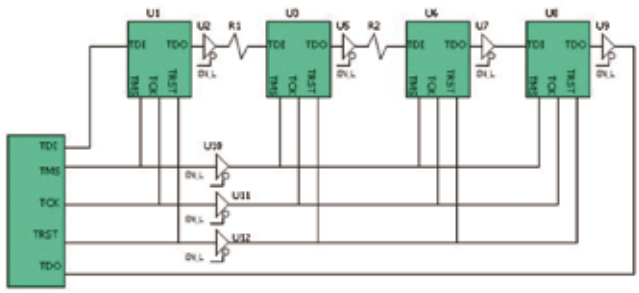
Boundary-Scan Chain Test



Boundary-Scan Cluster Test



Boundary-Scan Virtual Nails Test



Multi-Chip BSDL Test

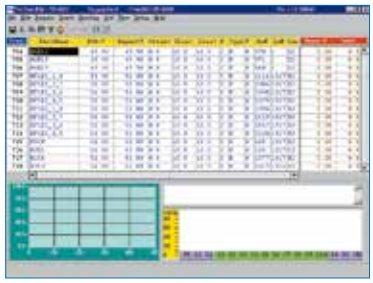
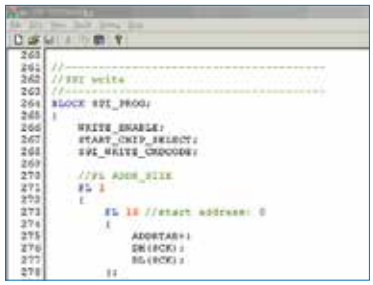
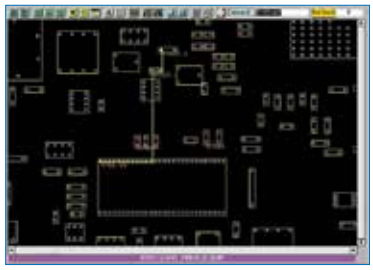


Table-based test program editor

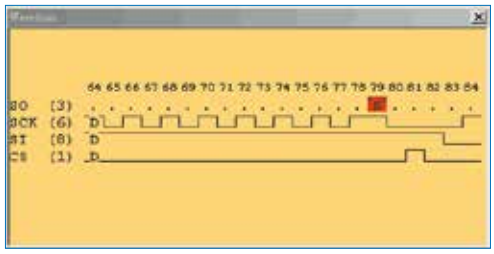
Simple test GUI



Color syntax program editor



Board view with trace display capability



Waveform display

USER-FRIENDLY INTERFACE

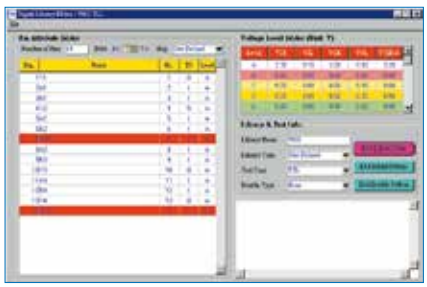
TR8100LV provides a simple-to-understand flexible interface

- Color syntax program editor
- C-like test language
- Editable waveform display tool
- Integrated development environment

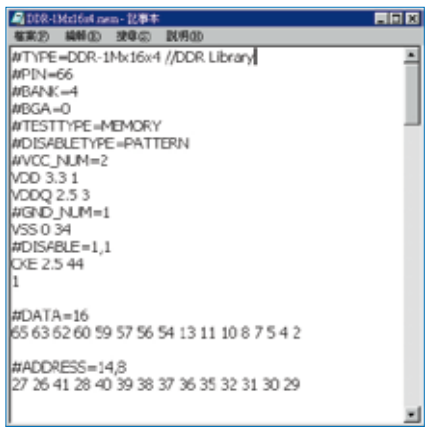
EASY MODEL DEVELOPMENT

Narrative library structure for fast and easy edits

- Import pin information
- Library syntax check
- Integrated GUI for all device types

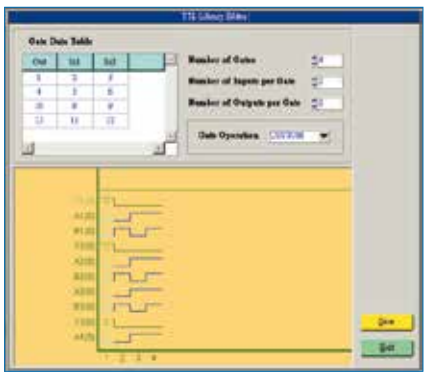


Import pin information

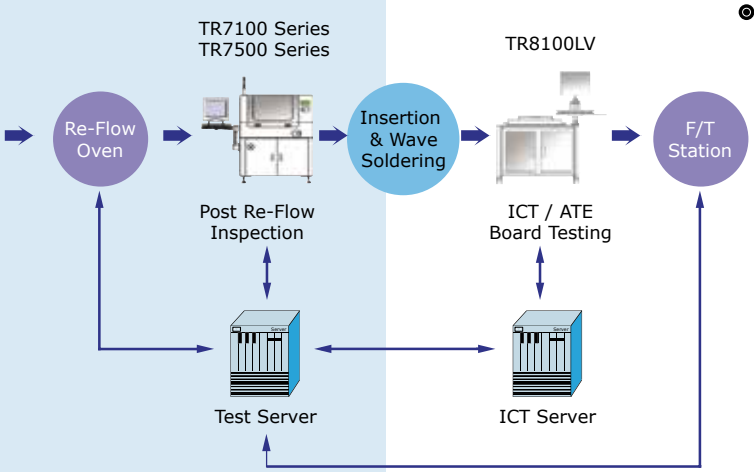


```
#TYPE=DDR-1Mx16x4 //DDR Library
#PIN=66
#BANK=4
#BGA=0
#TESTTYPE=MEMORY
#DISABLETYPE=PATTERN
#VCC_NUM=2
VDD 3.3 1
VDDQ 2.5 3
#GND_NUM=1
VSS 0 34
#DISABLE=1,1
CKE 2.5 44
1

#DATA=16
65 63 62 60 59 57 56 54 13 11 10 8 7 5 4 2

#ADDRESS=14,8
27 26 41 28 40 39 38 37 36 35 32 31 30 29
```

Library



Library edit tool



Network setup tool

SHOP FLOOR SYSTEM SUPPORT

- Supports text file, database, and DLL interfaces.
- S/N and operator ID check.
- Multi-data exchange protocol.

THE MOST COST-EFFECTIVE TEST STRATEGY

Non-Multiplexing Pin Design, Driver/Receiver Ratio 1:1

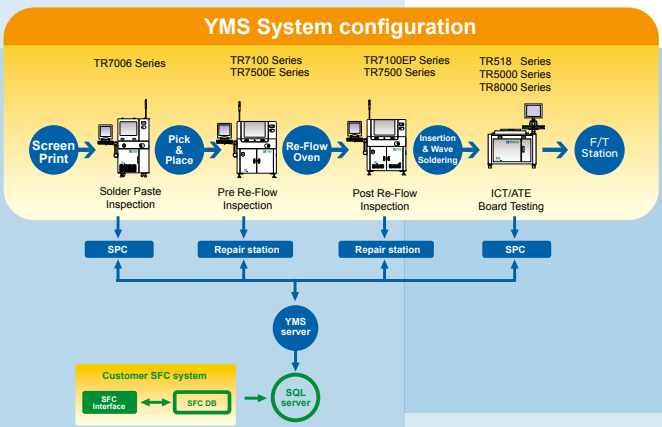
- Optimized Nail Placement with 1:1 Ratio Flexibility.
- ECNs do not require moving existing wires in your fixture.
- 1:1 Driver/Receiver pins provide for the fastest test program development and debugging solutions available.

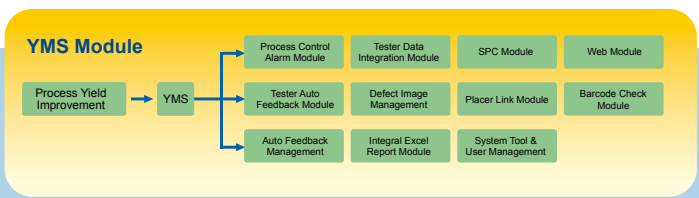
GENRAD AND TERADYNE CONVERSION TOOLKITS

There is no need to acquire new TRI fixtures because we can convert your existing GenRad or Teradyne ones.

PCBA YIELD MANAGEMENT SYSTEM

TRI's Yield Management System (YMS) is an omni-directional, integrated solution for today's manufacturing environment. It gathers and analyzes data from all TRI systems on the shop floor and delivers it an a user-friendly report format. TRI's YMS is a flexible system to meet the present and future needs of high-volume manufacturers.





GENERAL

Test Points	TR8100LV Expandable to 3584, TR8100L LV Expandable to 5632
Operating System	Microsoft Windows 10
Power Requirement	200-240 VAC, single phase, 50/60 Hz, 4 kVA
Fixture Type	Vacuum Type Option: Pneumatic Type

ANALOG HARDWARE

Measurement Switching Matrix

6-wire measurement

2 Programmable Voltage Source	DC 0 ~ ±10V, AC 0 ~ 7Vrms
1 Programmable High Voltage Source	DC 45V, 50mA Max.
1 Programmable Current Source	DC 100mA Max.

Analog Source

Component Measurement Capability

Resistance	0.1 ohm ~ 40M ohm
Capacitance	10pF ~ 40mF
Inductance	10uH ~ 60H

Arbitrary Waveform Generator(AWG)

2 Digitally synthesized stimulus sources configurable
Frequency range 0 ~ 100KHz, Resolution: 0.15Hz, BW: 100KHz Max.

Analog Measurement

AC Voltmeter	0 ~ 100Vp
DC Voltmeter	0 ~ ±100V

TestJet Technology

Vectorless Open Circuit Detection

DIGITAL HARDWARE

Non-Multiplexing 1:1 system per pin architecture

Pin Drivers	Programmable levels 0.5V to 4 V
Pin Receivers	Programmable levels -5V to 5V
Sink/Source Current	500mA Max.
Pull-up / pull-down Resistor	4.7K
DUT Power Supplies	5V@5A,3.3V@5A,12V@5A,0.2 ~ 20V@3A,-3 ~ -20V@3A
On- Board Programming of Flash & EEPROM Memories	Support the Binary Code Input Without Coding Environment
MAC Address Programming	Supports MAC Address Programming with MAC address being supplied from server

OPTIONS

Boundary Scan	B-Scan Chain Test, B-Scan Cluster Test & B-Scan Virtual Nails Test Facilities
DUT Power Supplies	Programmable 75Vmax, 8Amax(Max Power <200W)

Fixture Converter Kits available for GenRad &Teradyne

DIMENSIONS / WEIGHT

TR8100LV	1150 mm(W) x 850 mm(D) x 830 mm(H) / 390kg(Max) (45.28" x 33.46" x 32.68" / 858lbs.)
TR8100L LV	1550 mm(W) x 850 mm(D) x 830 mm(H) / 450kg(Max) (61.02" x 33.46" x 32.68" / 990lbs.)

POWERFUL SOFTWARE ENVIRONMENT

Microsoft Windows operating system software. User-friendly interface
Automatic Test Program Generator
Automatic disable generator of surrounding components
Automatic test generation with Auto-learning of open/short, IC Clamping Diode and TestJet technology
Auto debugging of passive components.
Built-in system self-diagnostic function
Paperless repair station & real-time process monitoring
Time selectable quality management and statistical reports
Board view instantly displays failing device and pin

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